


<b>Search Notes</b>  	<b>Application/Control No.</b>  10526427	<b>Applicant(s)/Patent Under Reexamination</b>  TAKAGAWA ET AL.
	<b>Examiner</b>  Hevey, John A	<b>Art Unit</b>  1793

SEARCHED			
Class	Subclass	Date	Examiner
252	62.56-62.59, 62.62-62.63	10/11/2007, 4/8/2008	jah

SEARCH NOTES		
Search Notes	Date	Examiner
EAST see search history	10/11/2007, 4/8/2008	jah
PALM inventor search	10/11/2007	jah

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner